

SN54HC365, SN74HC365 HEX BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS308B – JANUARY 1996 – REVISED MAY 1997

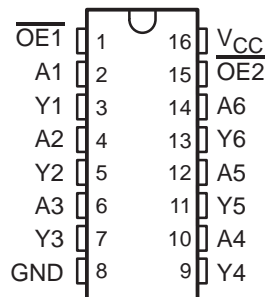
- High-Current 3-State Outputs Drive Bus Lines, Buffer Memory Address Registers, or Drive up to 15 LSTTL Loads
- True Outputs
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

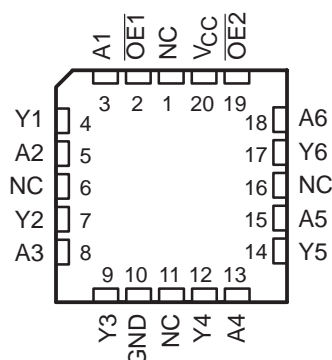
These hex buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC365 contain six independent buffers/drivers with dual-gated output-enable ($\overline{OE1}$ and $\overline{OE2}$) inputs. When $\overline{OE1}$ and $\overline{OE2}$ are both low, the device passes noninverted data from the A inputs to the Y outputs. If either (or both) output-enable terminal(s) is high, the outputs are in the high-impedance state.

The SN54HC365 is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74HC365 is characterized for operation from -40°C to 85°C .

SN54HC365 . . . J OR W PACKAGE
SN74HC365 . . . D OR N PACKAGE
(TOP VIEW)



SN54HC365 . . . FK PACKAGE
(TOP VIEW)



NC – No internal connection

FUNCTION TABLE
(each buffer/driver)

INPUTS			OUTPUT Y
$\overline{OE1}$	$\overline{OE2}$	A	
H	X	X	Z
X	H	X	Z
L	L	H	H
L	L	L	L



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

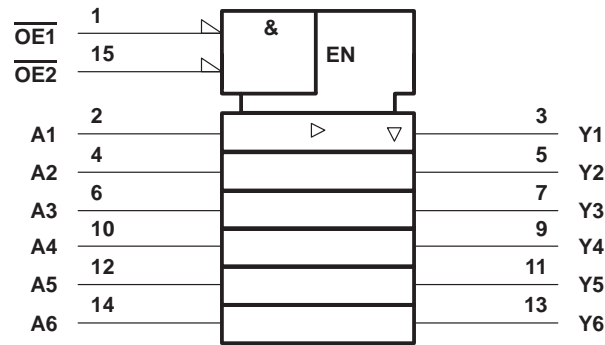
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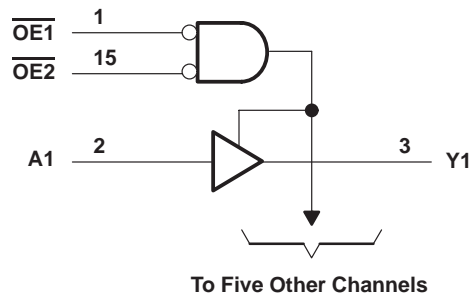
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logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for the D, J, N, and W packages.

logic diagram (positive logic)



Pin numbers shown are for the D, J, N, and W packages.

absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V_{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±35 mA
Continuous current through V_{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): D package	113°C/W
N package	78°C/W
Storage temperature range, T_{stg}	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

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recommended operating conditions

			SN54HC365			SN74HC365			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage		2	5	6	2	5	6	V
V _{IH}	High-level input voltage	V _{CC} = 2 V	1.5			1.5			V
		V _{CC} = 4.5 V	3.15			3.15			
		V _{CC} = 6 V	4.2			4.2			
V _{IL}	Low-level input voltage	V _{CC} = 2 V	0			0			V
		V _{CC} = 4.5 V	0			1.35			
		V _{CC} = 6 V	0			1.8			
V _I	Input voltage		0			V _{CC}			V
V _O	Output voltage		0			V _{CC}			V
t _t	Input transition (rise and fall) time	V _{CC} = 2 V	0			0			ns
		V _{CC} = 4.5 V	0			500			
		V _{CC} = 6 V	0			400			
T _A	Operating free-air temperature		−55			125			°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V _{CC}	T _A = 25°C			SN54HC365		SN74HC365		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
V _{OH}	V _I = V _{IH} or V _{IL}	I _{OH} = –20 µA	2 V	1.9	1.998		1.9		1.9		V
			4.5 V	4.4	4.499		4.4		4.4		
			6 V	5.9	5.999		5.9		5.9		
		I _{OH} = –6 mA	4.5 V	3.98	4.3		3.7		3.84		
		I _{OH} = –7.8 mA	6 V	5.48	5.8		5.2		5.34		
V _{OL}	V _I = V _{IH} or V _{IL}	I _{OL} = 20 µA	2 V		0.002	0.1		0.1		0.1	V
			4.5 V		0.001	0.1		0.1		0.1	
			6 V		0.001	0.1		0.1		0.1	
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		I _{OL} = 7.8 mA	6 V		0.15	0.26		0.4		0.33	
I _I	V _I = V _{CC} or 0		6 V		±0.1	±100		±1000		±1000	nA
I _{OZ}	V _O = V _{CC} or 0		6 V		±0.01	±0.5		±10		±5	µA
I _{CC}	V _I = V _{CC} or 0, I _O = 0		6 V			8		160		80	µA
C _i			2 V to 6 V		3	10		10		10	pF

SN54HC365, SN74HC365

HEX BUFFERS AND LINE DRIVERS

WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	$T_A = 25^\circ\text{C}$			SN54HC365		SN74HC365		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A	Y	2 V		50	95		145		120	ns
			4.5 V		12	19		29		24	
			6 V		10	16		25		20	
t_{en}	\overline{OE}	Y	2 V		100	190		285		238	ns
			4.5 V		26	38		57		48	
			6 V		21	32		48		41	
t_{dis}	\overline{OE}	Y	2 V		50	175		265		240	ns
			4.5 V		21	35		53		48	
			6 V		19	30		45		41	
t_t		Any	2 V		28	60		90		75	ns
			4.5 V		8	12		18		15	
			6 V		6	10		15		13	

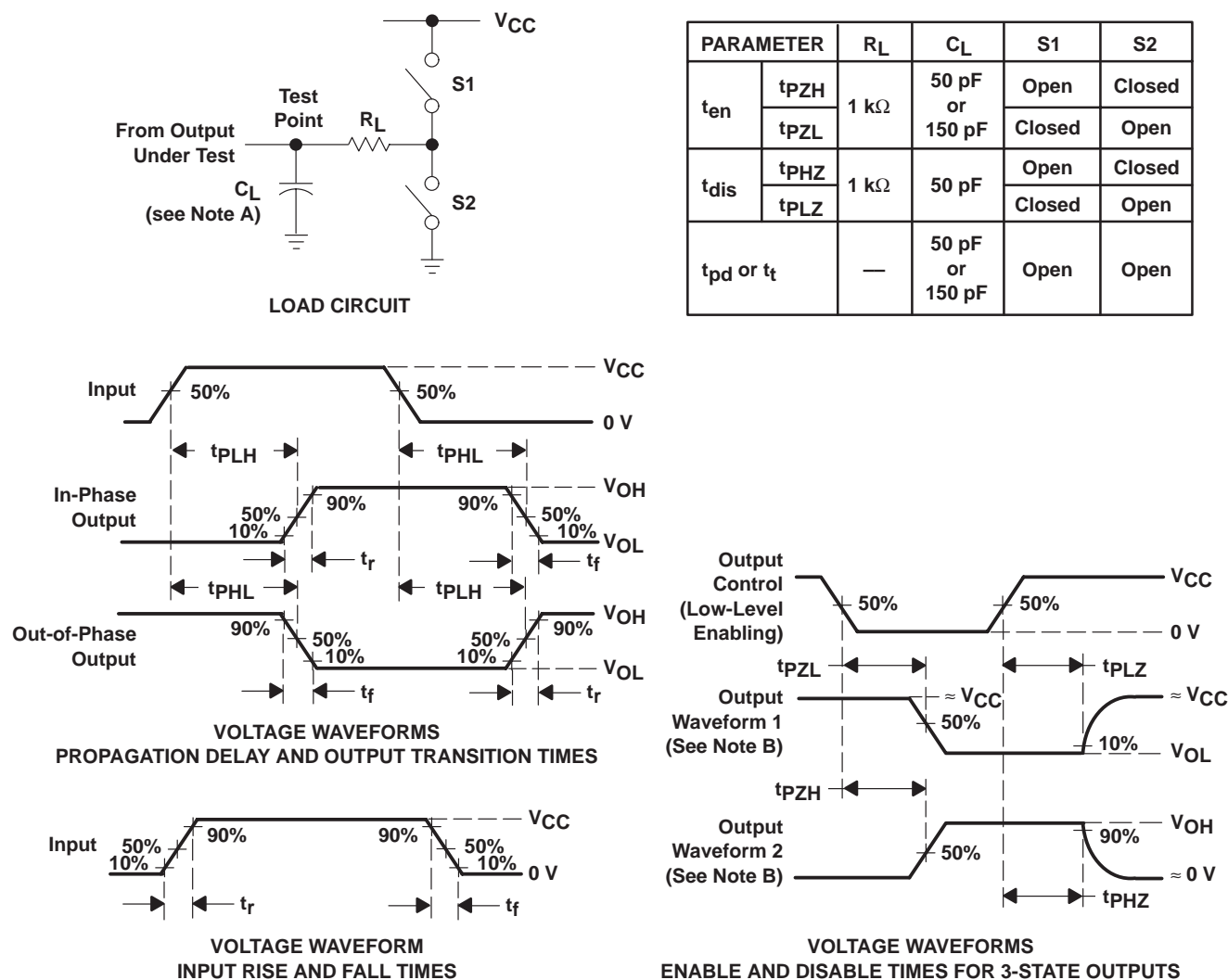
switching characteristics over recommended operating free-air temperature range, $C_L = 150$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC}	$T_A = 25^\circ\text{C}$			SN54HC365		SN74HC365		UNIT
				MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t_{pd}	A	Y	2 V		70	120		180		150	ns
			4.5 V		17	24		36		30	
			6 V		14	20		31		25	
t_{en}	\overline{OE}	Y	2 V		140	230		345		285	ns
			4.5 V		30	46		69		57	
			6 V		28	39		59		48	
t_t		Any	2 V		45	210		315		265	ns
			4.5 V		17	42		63		53	
			6 V		13	36		53		45	

operating characteristics, $T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C_{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES:
- A. C_L includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: $PRR \leq 1\text{ MHz}$, $Z_O = 50\text{ }\Omega$, $t_r = 6\text{ ns}$, $t_f = 6\text{ ns}$.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. tp_{LH} and tp_{HL} are the same as t_{pd} .
 - F. tp_{LZ} and tp_{HZ} are the same as t_{dis} .
 - G. tp_{ZL} and tp_{ZH} are the same as t_{en} .

Figure 1. Load Circuit and Voltage Waveforms

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